



DSD'2005
EUROMICRO CONFERENCE ON
DIGITAL SYSTEM DESIGN
Architectures, Methods and Tools
August 30 - September 3, 2005, Porto, Portugal
Call for Papers

Session Organizer:

Hana Kubátová

Czech Technical University in Prague
(CZ)

Contact Information:

Hana Kubátová
Czech Technical Univ. in Prague
Dept. of Computer Science and
Engineering

Karlovo nám. 13
CZ-12135, Prague
kubatova@fel.cvut.cz
Tel. +420 224 357 281
Fax +420 224 923 325

Program Committee:

P. Fišer, CTU in Prague (CZ)
A. Hlawiczka, Silesian TU Gliwice (PL)
Z. Kotásek, TU Brno (CZ)
H. Kubátová, CTU in Prague (CZ)
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Special Session: SS2

DEPENDABILITY AND TESTING OF DIGITAL SYSTEMS

BACKGROUND

The Euromicro Conference on Digital System Design addresses all aspects of (embedded) digital and mixed hardware/software system engineering. It is a discussion forum for researchers and engineers working on state-of-the-art investigations, development, and applications. It focuses on advanced system design and design automation concepts, paradigms, methods and tools, as well as modern implementation technologies. Every designed system has to be tested several times during its life period - during its design, production and its functionality. The necessity of testing strictly depends on the real using of the system, e.g. if the system can be repaired or not, if the system must be safe, etc. The design must reflect these conditions.

SCOPE

The special session on "Dependability and Testing of Digital Systems" addresses emerging issues, hot problems, new solution methods and their hardware and software implementations in all fields of digital and mixed-signal system dependability and testing. Its special focus is on the dependability and testing related to the SoC technology and modern embedded applications:

- Built-in Self-Test: Off-Line BIST and On-Line BIST
- On-line Testing
- IDDQ and Current Testing
- Defect/Fault Tolerance
- Dependability and Reliability - Modeling and Computations
- Design for Testability
- Diagnosis Embedded Test
- Analog, Mixed-Signal and RF Test
- Memory and Processor Test

SUBMISSION OF PAPERS

Prospective authors are encouraged to submit their manuscripts for review electronically through the following web page (<http://dsd2005.irisa.fr/confman/>) or by sending the paper to the Program Chair via email dsd05-papers@listes.univ-rennes1.fr (only in the case of the web access problem) before the deadline for submission (*please indicate the topic area as: SS2*) Each manuscript should include all text, illustrations, and references. The manuscript should conform to the required format single-spaced, double column, A4/US letter page size, 10-point size Times Roman font, up to 8 pages. The DSD'2005 web page should be consulted for the exact submission format.

The Proceedings of DSD'2005 will be published by the IEEE Computer Society.

IMPORTANT DATES

Submission of papers: March 1, 2005
Notification of acceptance: May 3, 2005
Deadline for final version: June 9, 2005

Special Session web page:

<http://service.felk.cvut.cz/vlsi/dsd05/>

DSD'05 web page: <http://dsd2005.univ-rennes1.fr>

Euromicro web page: <http://www.euromicro.org>

DSD web page: <http://www.dsdconf.org>